

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination	
		10/665,440	SKINLO, DAVID M.	
Examiner		Art Unit		Page 1 of 1
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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,114,059	09-2000	Watanabe et al.	429/120
*	B	US-6,387,561	05-2002	Nemoto et al.	429/51
	C	US-			
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	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

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